Extreme Broadband Silicon Capacitor XBSC 0201M 1nF BV30

Rev. 3.04

General description

Market: XBSC Capacitor targets Optical communication system such as ROSA/TOSA, SONET and all optoelectronics as well as High speed data system or products.
The XBSC is suitable for DC blocking, feedback, coupling and bypassing applications in all broadband optoelectronics and High-speed data system.
The unique technology of integrated passive device in silicon, developed by Murata Integrated Passive Solutions, offers unique performances with low insertion loss, low reflection and phase stability from 1600 KHz to 150 GHz.
These capacitors in ultra-deep trenches in silicon have been developed in a semiconductor process, in order to integrate trench MOS capacitor providing high capacitance value of 1nF (for kHz–MHz range) and MIM capacitors for low capacitance value (for GHz range), both in a SMT 0201M (0.6 x 0.3mm).
The XBSC capacitor provides very high stability of the capacitance over temperature, voltage variation as well as a very high reliability.

XBSC capacitors have an extended operating temperature ranging from -55 to 150°C, with very low capacitance change over temperature.

Assembly: Suitable for surface mounted application on rigid PCB, ceramic substrate, FR4 (laminate) or flex platforms.

Bump finishing: SAC305 type 6.
Copper pads optional for embedding version and ENIG for un-bumped version, as an optional finishing.

Key features

- Ultra large band performance to 150 GHz
- Resonance free
- Phase stability
- Insertion low < 0.6dB Typ. up to 150 GHz
- Ultra-high stability of capacitance value:
  - Temperature 70ppm/K (-55 °C to +150 °C)
  - Voltage <-0.1%/Volts
  - Negligible capacitance loss through ageing
- Low profile: 140µm including bump height
- Break down voltage : 30V
- Low leakage current < 70pA
- High reliability
- High operating temperature (up to 150 °C)
- Compatible with high temperature cycling during manufacturing operations (exceeding 300 °C)
- Compatible with EIA 01005 footprint and with EIA 0201 outline
- SAC305 40µm bumps after reflow

Key applications

- ROSA/TOSA
- SONET
- High speed digital logic
- Microwave/millimetre system
- High volumetric efficiency (i.e. *capacitance* per unit *volume)*
- Broadband test equipment

Functional diagram

The next figure provides implementation set-up diagram.

Figure 1 Block Diagram

Electrical performances

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
C	Capacitance value	@+25°C	-	1	-	nF
ΔC_P	Capacitance tolerance (1)	@+25°C	-15	-	+15	%
T_{OP}	Operating temperature		-55	20	150	°C
T_{STG}	Storage temperature (2)		-70	-	165	°C
ΔC_T	Capacitance temperature variation	-55 °C to 150 °C	-	70	-	ppm/K
RV_{DC}	Rated voltage (3)		-	-	16(4) 14.7(5)	V_{DC}
BV	Break down voltage	@+25°C	30	-	-	V
ΔC_{RVDC}	Capacitance voltage variation	From 0 V to RV_{DC}, @+25°C	-	-	-0.1	%/V_{DC}
IR	Insulation resistor	@RV_{DC}, +25°C, 120s	-	10	-	GΩ
ESL	Equivalent Serial Inductance	@+25°C, SRF shunt mode	-	50	100	pH
ESR	Equivalent Serial Resistance	@+25°C, shunt mode	-	400	600	mOhm
Fc-3dB	Cut-off frequency at 3dB	@+25°C	-	1600	1872	kHz
IL	Insertion loss	@ 20 GHz, +25°C	-	0.1	-	dB
		@ 40 GHz, +25°C	-	0.2	-	dB
		@ 60 GHz, +25°C	-	0.3	-	dB
		@ 150 GHz, +25°C	-	0.3	-	dB
RL	Return loss	Up to 150 GHz, +25°C	12	-	-	dB
ESD	HBM stress (6)	JS-001-2017	8	-	-	kV

Table 1 - Electrical performances

(1): other tolerance available upon request
(2): without packaging
(3): Lifetime is voltage and temperature dependent, please refer to application note 'Lifetime of 3D capacitors'
(4): 10 years of intrinsic lifetime prediction at 100°C continuous operation
(5): 10 years of intrinsic lifetime prediction at 150°C continuous operation
(6): please refer to application note 'ESD Challenge in 3D Murata Integrated Passive technology'

Module S-parameters of 1nF XBSC in transmission mode

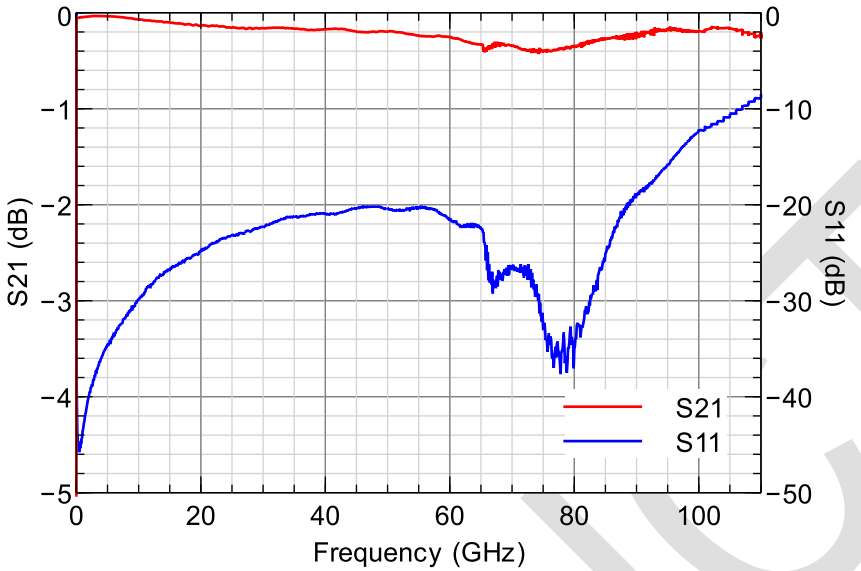
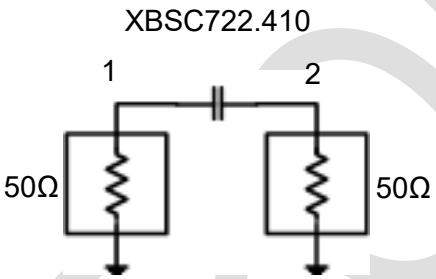


Figure 2 – 1nF XBSC measurement results (module of S-parameters)

Schematic of 1nF XBSC in transmission mode



4-mil Rogers 4350B.
Microstrip mode – line width = 0.200mm and gap = 0.200 mm.
(nominal 50 ohm characteristic impedance).

Figure 3 – 1nF XBSC measurement schematic

Example of surface mounted 0201M

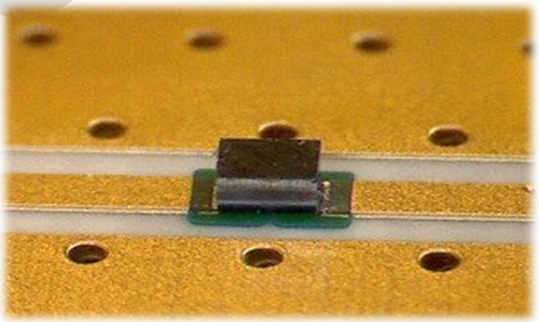


Figure 4 – micro picture of XBSC mounted on board in coplanar mode

Pinning definition

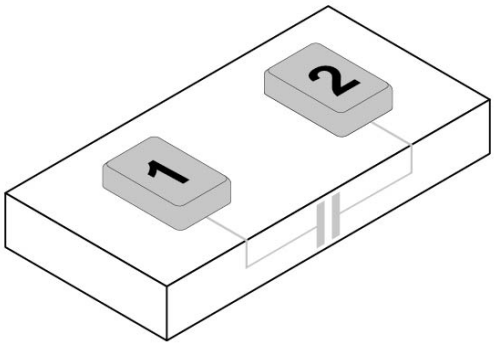


Figure 5 Pin configuration

pin #	Symbol	Coordinates X / Y
1	Signal	-150.0 / 0.0
2	Signal	150.0 / 0.0

Table 2 - Pining description. Reference (0,0) located at the centre of the die.

Ordering Information

Part number	Package		
	Packaging (1)	Finishing	Description
939118722410-T3S	7" T&R (1 000 pieces/reel) (3) (5)	SAC (2)	XBSC 0201M – 1nF – 2 pads – 0.60mm x 0.30mm x 0.14mm (4)
939118722410-T3N	7" T&R (1 000 pieces/reel) (3) (5)	ENIG (2)	XBSC 0201M – 1nF – 2 pads – 0.60mm x 0.30mm x 0.14mm (4)
939118722410-T5S	7" T&R (5 000 pieces/reel) (3) (6)	SAC (2)	XBSC 0201M – 1nF – 2 pads – 0.60mm x 0.30mm x 0.14mm (4)
939118722410-T5N	7" T&R (5 000 pieces/reel) (3) (6)	ENIG (2)	XBSC 0201M – 1nF – 2 pads – 0.60mm x 0.30mm x 0.14mm (4)

Table 3 - Packaging and ordering information

(1) Other Film Frame Carrier are possible on request
(2) SAC = ENIG (0.1µm Au / 5µm Ni) + SAC305 type 6 or ENIG 0.1µm Au / 5µm Ni
(3) Missing capacitors can reach 0.5%
(4) Refer to Figure
(5) Dedicated for Pre-Production
(6) For all demands including Mass Production

Product Name	Die Name	Description
XBSC722.410	XJM0201410	XBSC 1nF/0201M/BV30 – 2 pads – 0.6 x 0.3 x 0.14 mm (3)

Table 4 - Die information

Pad Metallization

The Surface Mounted Capacitor is delivered as standard with SAC305 type6 bumping.

Other Metallization, such as ENIG (0.1µm Au / 5µm Ni), Copper, Thick Gold or Aluminum pads are possible on request.

Silicon dies are not sensitive to humidity, please refer to applications notes 'Assembly Notes' section 'Handling precautions and storage'.

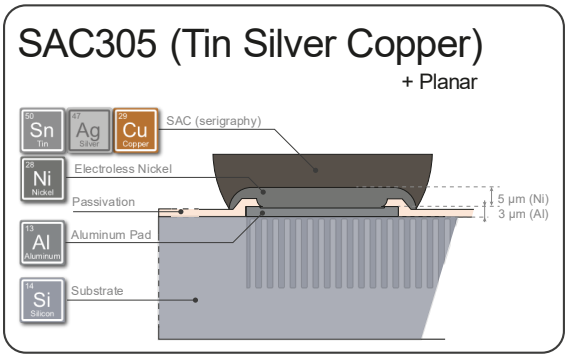


Figure 6 – Top electrode description of SAC305 pre-bumped version

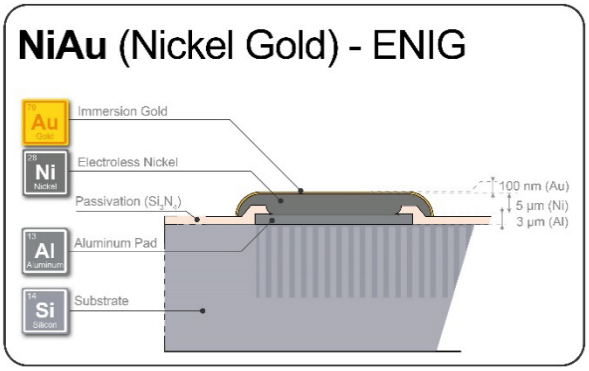


Figure 7 – Top electrode description of ENIG finishing version

Material regulation

This product is RoHS compliant at the time of publication. For further information about regulation compliancy, please ask your sales representative.

Package outline

The product is delivered as a bare silicon die.

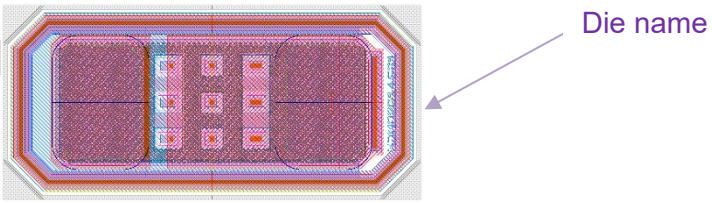


Figure 8 – Layout view

	L (mm)	W (mm)	T (mm)	c (mm)	p (mm)	e (mm)	t (mm)
Component dimension	0.60 ±0.02	0.30 ±0.02	0.11 max	0.10	0.20	0.15	0.04(1) 0.05(2) 0.005 (3)
Landing pad recommendation	/	/	/	0.114 min	0.186 max	0.164 min	/

(1) Standard with solder joint height after reflow on board.
(2) Standard with solder bump height before assembly
(3) Only in case of ENIG finishing

Table 5 - Dimensions and tolerances

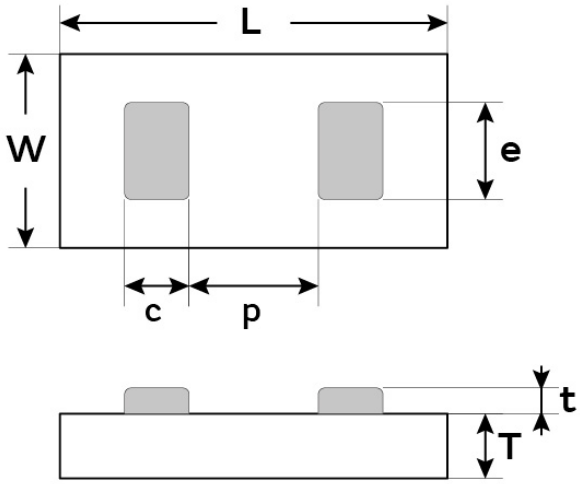


Figure 9 - Package outline drawing

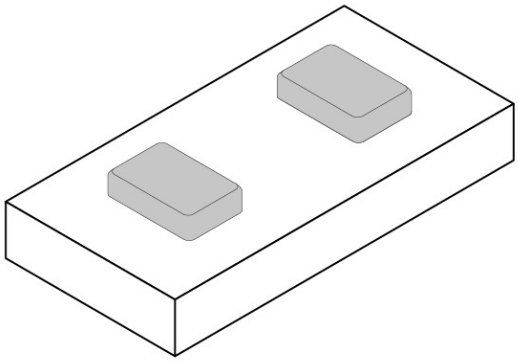


Figure 10 Isometric view

Assembly

XBSC series is compatible with standard reflow technology.

It is recommended to design mirror pads on the PCB.

For further information, please see our mounting application note

The attachment techniques recommended by Murata on the customer's substrates are fully detailed in specific documents available on our website. To assure the correct use and proper functioning of Murata capacitors **please download the assembly instructions on https://www.murata.com/en-us/products/capacitor/siliconcapacitors and read them carefully.**

Figure 11 Scan this QR Code to access the Murata Silicon Capacitor web page

Packaging format

Please refer to application note 'Products Storage Conditions and Shelf Life'.

Tape and Reel: Dies are flipped in the tape cavity (bump down) with die ID located near the driving holes of the tape.

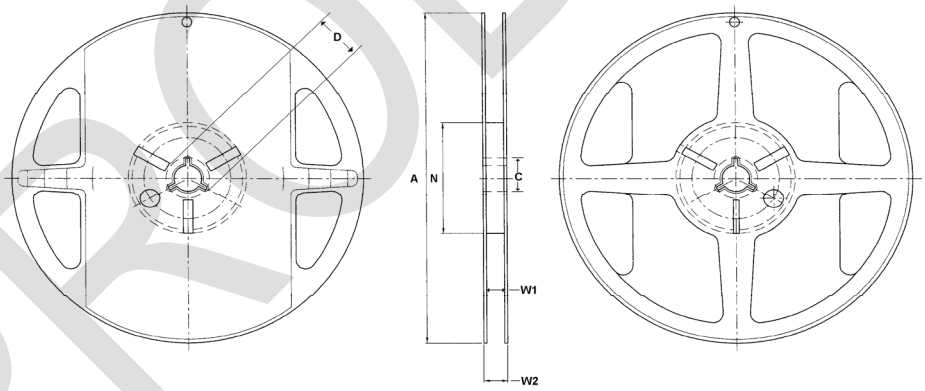


Figure 12 - Reel drawing

Tape Width	Diameter A	C	D	Hub N	W1	W2
8	178 (7 inches)	13.5	21	60	9.5	11.4

Table 6 - Reel dimensions (mm)

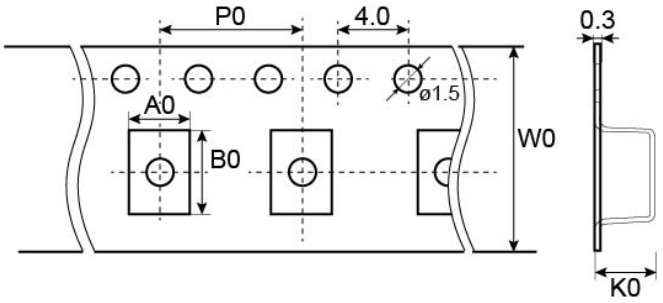


Figure 13 - Tape drawing

Cavity dimensions			Carrier tape width W0	Carrier tape pitch P0	Reel Capacity
Ao	Bo	Ko			
0.37 +/-0.04	0.67 +/-0.04	0.20 +/-0.04	8.00	2.00	1000 or 5000

Table 7 - Tape dimensions (mm)

Definitions

Data sheet status

Objective specification: This data sheet contains target or goal specifications for product development.

Preliminary specification: This data sheet contains preliminary data; supplementary data may be published later.

Product specification: This data sheet contains final product specifications.

Limiting values

Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or any other conditions above those given in the Electrical performances sections of this specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

Application information

Where application information is given, it is advisory and does not form part of the specification.

Revision history

Revision	Date	Description	Author
Release 1.00	2017 June 5th	Objective specification	OGA
Release 2.04	2020 Oct. 1st	Packaging update	SCA / OGA
Release 3.00	2021 Jul. 15th	Minor update	SCA / OGA
Release 3.01	2023 March 10th	Packaging update	CGU
Release 3.02	2023 Nov. 2nd	Extended high frequency limit	DYE, OGA
Release 3.03	2025 Jan 15th	Complementary land pattern information	MOK+ DYE + OGA
Release 3.04	2025 Oct 21st	Ordering information has been updated according to the latest product lineup and specification.	CGU, HFU

Disclaimer / Life support applications

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